

et No.: 50090-332

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of : Customer Number: 20277

Hisaya MORI, et al. : Confirmation Number: 4507

Seriai No.: 09/927,368 : Group Art Unit: 2829

Filed: August 13, 2001 : Examiner: Chan, Emily T.

For: APPARATUS AND METHOD FOR TESTING SEMICONDUCTOR INTEGRATED

CIRCUIT

INFORMATION DISCLOSURE STATEMENT

Mail Stop IDS Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Dear Sir:

In accordance with the provisions of 37 C.F.R. 1.56, 1.97 and 1.98, the attention of the Patent and Trademark Office is hereby directed to the documents listed on the attached form PTO-1449. It is respectfully requested that the documents be expressly considered during the prosecution of this application, and that the documents be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

Please note that Japanese Laid-Open publication No. 2000-356724 is not related to this application. Japanese Laid-Open publication No. 2002-162450 (Application No. 2000-356724) is the correct prior art relating to this application.

This Information Disclosure Statement is being filed more than three months after the U.S. filing date AND after the mailing date of the first Office Action on the merits, but before the mailing date of a Final Rejection or Notice of Allowance.

09/927,368

In accordance with 37 CFR 1.17(p), please charge the fee of \$180.00 to Deposit Account No. 500417.

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Respectfully submitted,

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Date: September 16, 2003

SHEET 1 OF 1

INFORMATION DISCLOSURE CITATION IN AN APPLICATION (PTO-1449)				ATTY. DOCKET NO. 50090-332	SERIAL NO. 09/927,368		
				APPLICANT Hisaya MORI, et al.			
				FILING DATE August 13, 2001			
	***************************************		U.S. PATEN	Γ DOCUMENTS	•		
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E AMINER'S INITIALS	CITE NO.	Foreign Patent Document Country Codes - Number 4 - Kind Codes (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages. Columns, Lines Wher Relevant Figures Appear	re	
		JP P2002-162450A	06/07/2002	MITSUBISHI ELECTRIC CORP RYODEN SEMICONDUCTOR SYST ENG CORP		Yes (Japan w/English Abstract)	No
E::AMINER'S INITIALS	CITE NO	Include name of the author (in	CAPITAL LETTERS	, Title, Date, Pertinent Pages, Etc.)), title of the article (when appropriate) e(s), volume-issue number(s), publish			-
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1 Applicant's unique citation designation number (optional). 2 Applicant is to place a check mark here if English language Translation is attached.